

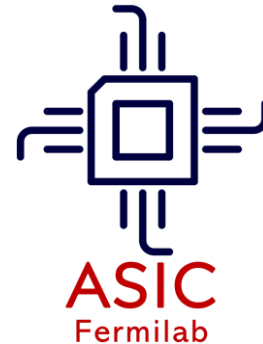


# ASIC Design and Development

Paul Rubinov

2021 All Engineers Retreat

24 Feb

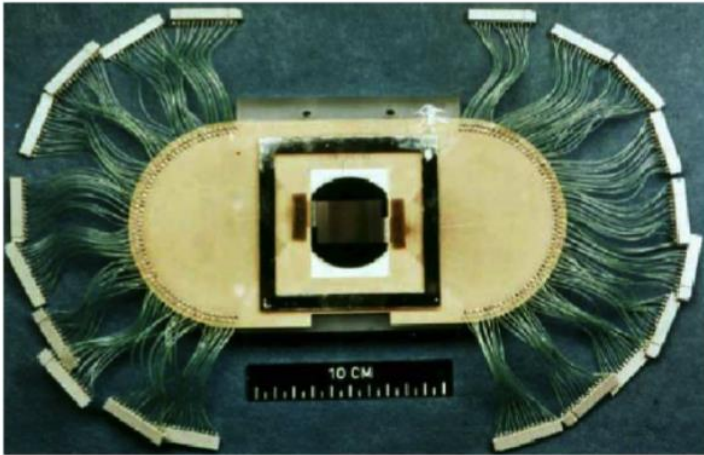


# The Fermilab ASIC Group

## Application Specific Integrated Circuits



The history of ASIC design for HEP is tied to the development of Si strip detectors.  
The first Fermilab ASIC : QPA02 (Quad Preamp), bipolar, semi-custom



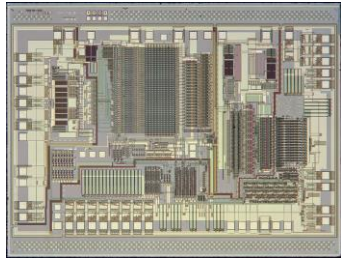
First Si strip detector at CERN  
NA11 (1981)  
60um readout pitch, 400 chan  
Readout > 1 sq meter



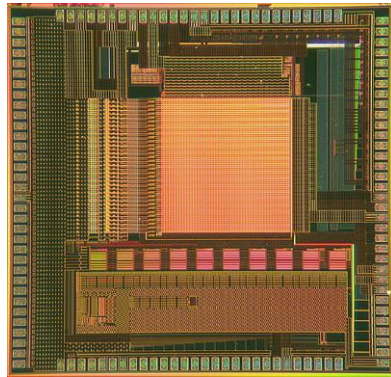
R. Yarema, "ASIC Design at Fermilab", FERMILAB-Conf-91/170

# Need for collider detectors drives full custom design in CMOS

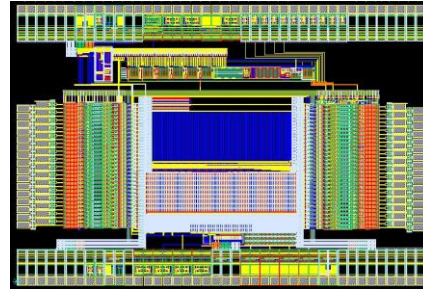
- By **2005**, Fermilab ASIC group is BUSY
  - 5 (!) ASIC engineers + Analog and Digital + Test engineers
  - Many projects, most in **TSMC 0.25um** (250nm)



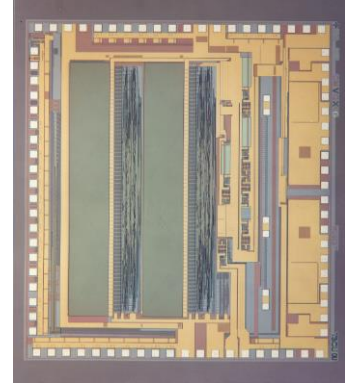
QIE9



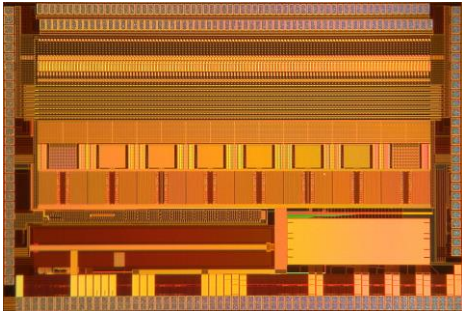
TriP-t



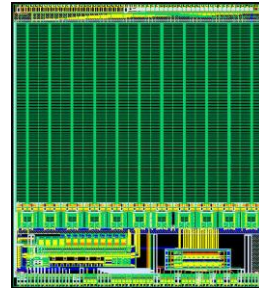
DCAL



RMCC



FSSR



FPIX2

+SVX4  
+MASDA(X)  
+APD RO (NOvA)  
Going to 130nm

# Today

## J. Hoff

C. Gingu

A. Shenai

C. Syal

R. Wickwire

(M. Hammer)

## S. Li

T. England

H. Sun

X. Wang

## G. Drake

D. Braga

Q. Sun

T. Zimmerman

## F. Fahim

Deputy Head  
Quantum Science  
Program, FQI

- + Test engineers, IT support, firmware support etc.

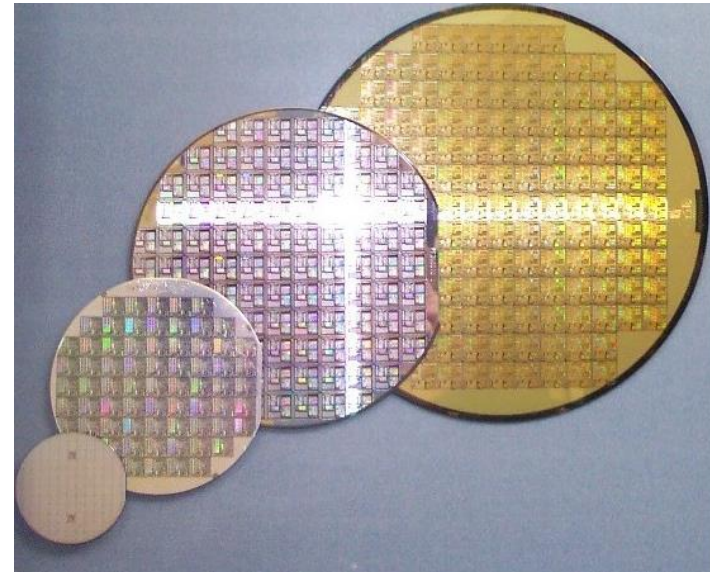
# The power of Integrated Circuits

- Moore and friends – digital scaling

Scaled Parameters	Constant field Scaling
$t_{ox}, L, W, X_j, W_d$	$1/\kappa$
$N_a, N_d$ (ions/cm <sup>3</sup> )	$\kappa$
Power supply: ( $V_{dd}$ )	$1/\kappa$
Electric field in device: ( $E$ )	1
Capacitance: ( $C$ )	$1/\kappa$
Inversion charge density ( $Q$ )	1
Circuit delay time: $\tau \sim C/I$	$1/\kappa$
Power dissipation: ( $P$ )	$1/\kappa^2$
Power density ( $\sim P/A$ )	1
Circuit density	$\kappa^2$
Chip Area ( $A$ )	$1/\kappa^2$

## MOSFET scaling (process nodes)

10  $\mu\text{m}$  – 1971  
 6  $\mu\text{m}$  – 1974  
 3  $\mu\text{m}$  – 1977  
 1.5  $\mu\text{m}$  – 1981  
 1  $\mu\text{m}$  – 1984  
 800 nm – 1987  
 600 nm – 1990  
 350 nm – 1993  
 250 nm – 1996  
 180 nm – 1999  
 130 nm – 2001  
 90 nm – 2003  
 65 nm – 2005  
 45 nm – 2007  
 32 nm – 2009  
 22 nm – 2012  
 14 nm – 2014  
 10 nm – 2016  
 7 nm – 2018  
 5 nm – 2020  
 Future  
 3 nm ~ 2022  
 2 nm ~ 2024



4in wafer  $\rightarrow$  300mm wafer

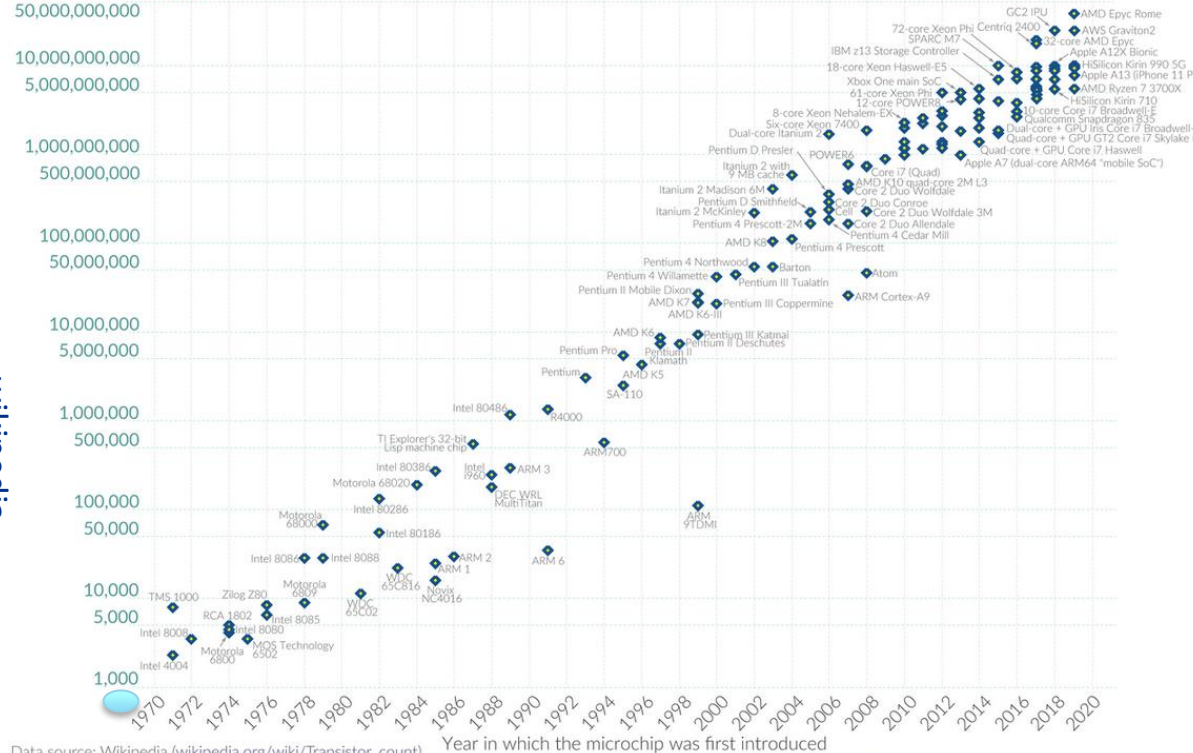
# Moore's law cont.

Moore's Law: The number of transistors on microchips doubles every two years

Moore's law describes the empirical regularity that the number of transistors on integrated circuits doubles approximately every two years. This advancement is important for other aspects of technological progress in computing – such as processing speed or the price of computers.

Our World  
in Data

Transistor count



1990: \$25K for  
prototype run

2020: \$40K for 55nm GF  
for 9mm<sup>2</sup> (50 chips)

Data source: Wikipedia ([wikipedia.org/wiki/Transistor\\_count](https://wikipedia.org/wiki/Transistor_count))

OurWorldinData.org – Research and data to make progress against the world's largest problems.

Licensed under CC-BY by the authors Hannah Ritchie and Max Roser.

# Analog scaling

P. O'Connor and G. De Geronimo

Prospects for charge sensitive amplifiers in scaled CMOS

NIM A 480 (2002) 713-725

Written exactly 20 yrs ago

Table 2  
System parameters for ENC scaling simulation

System	$C_{\text{det}}$	$t_s$	$P$	$I_{\text{leak}}$	Detector	Typical application
<i>a</i>	30	75	10	0.001	Wire chamber	Tracking, imaging
<i>b</i>	15	25	0.2	10	Si Strip	Tracking
<i>c</i>	0.3	25	0.02	1	Si Pixel	Tracking
<i>d</i>	3	2500–500 <sup>a</sup>	10	0.01	Semiconductor	Spectroscopy
UNITS	pF	ns	mW	nA	—	—

<sup>a</sup> For this system, the shaping time was varied at each  $L_g$  to optimize the overall noise (i.e., to make the white series noise and parallel noise equal).

# Analog scaling cont.

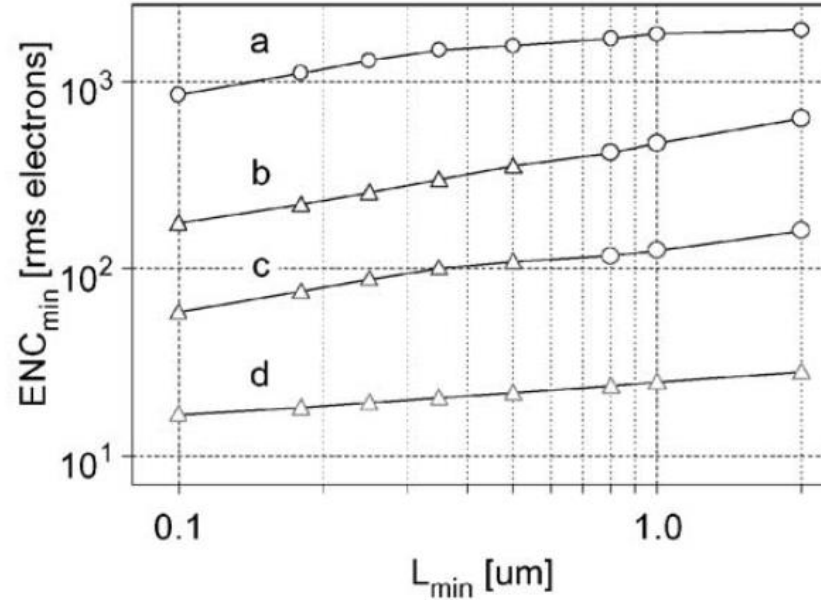


Fig. 6. Optimum total ENC as a function of the minimum gate length. Curves (a–d) refer to the system parameters given in Table 2. Circles = NMOS, triangles = PMOS.

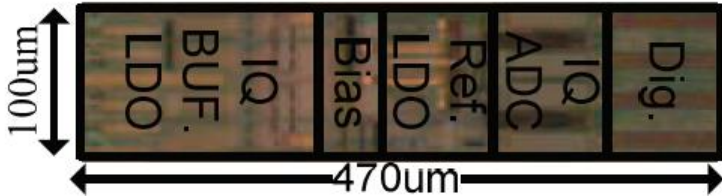


# ADC scaling

~10 to 14 bit,  
100MSPS

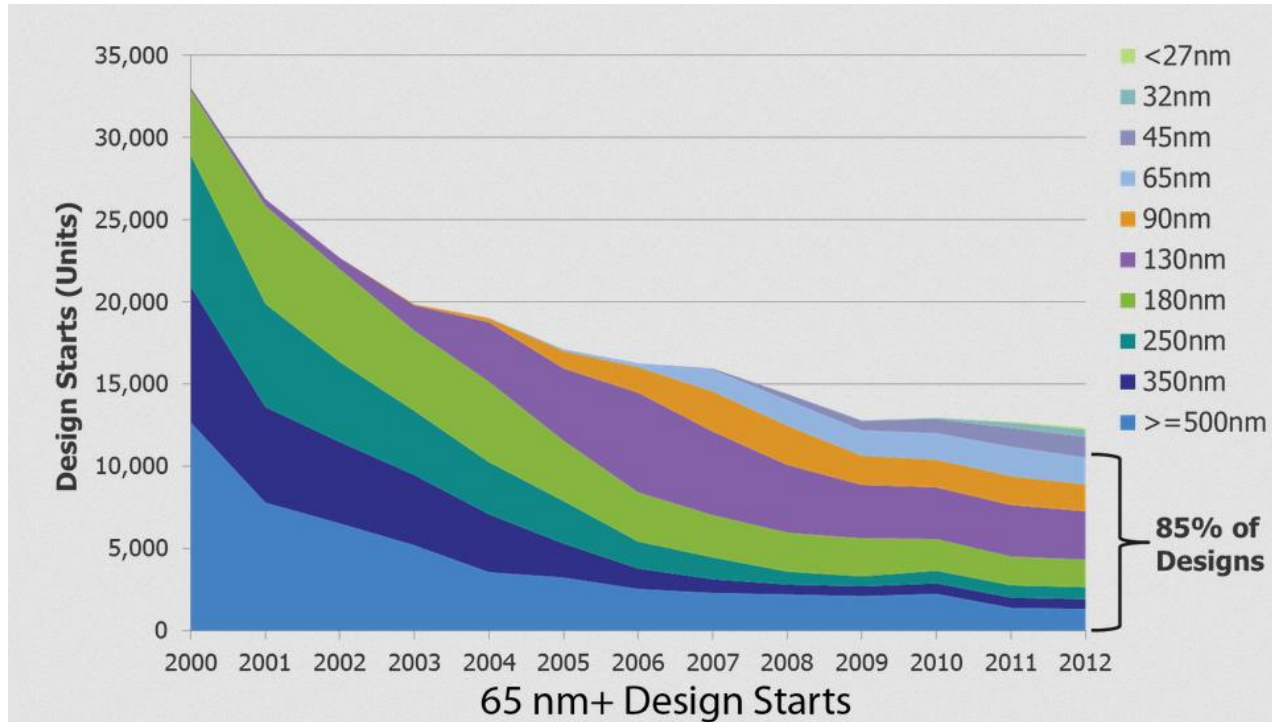
$$\text{FOM} = \text{Power} / (2^{\text{ENOB}} * \text{freq})$$

Technology	Year	Area (sq mm)	FOM (fJ/step)
250nm	2010	4.5	344
180nm	2012	0.5	89
130nm	2012	0.24	31
65nm	2012	0.19	46
28nm	2015	0.047	13

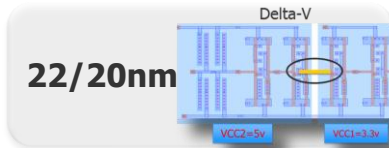


# The power of Application Specific

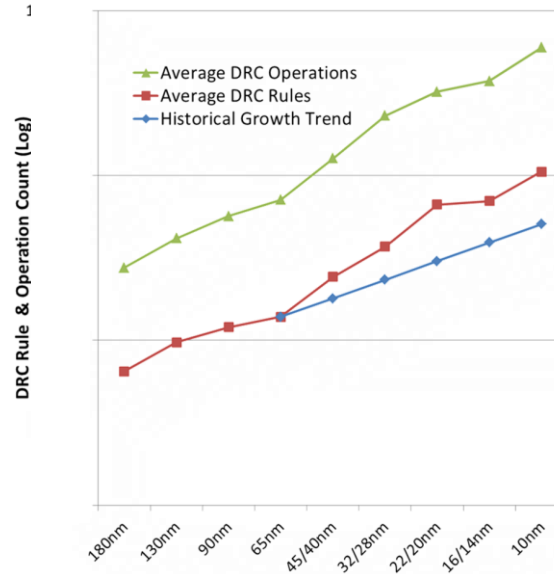
- Moore's law does not drive design decisions

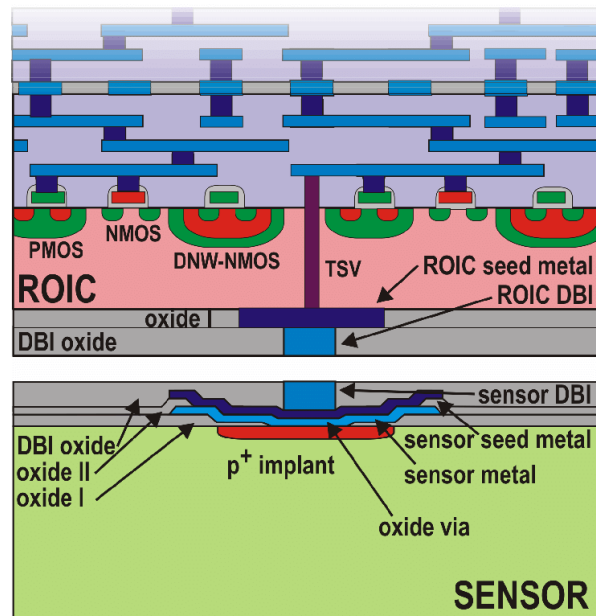
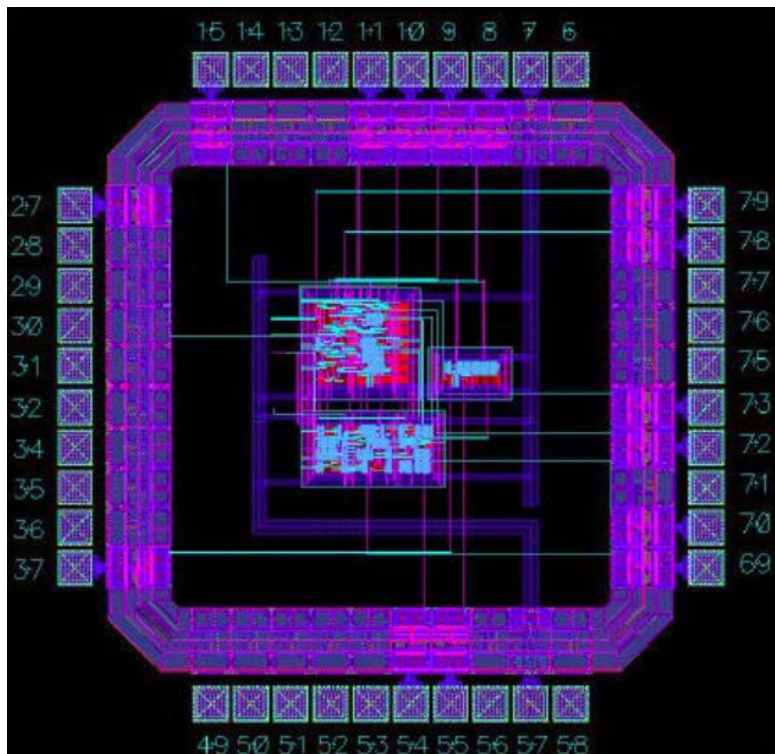


## Functionality

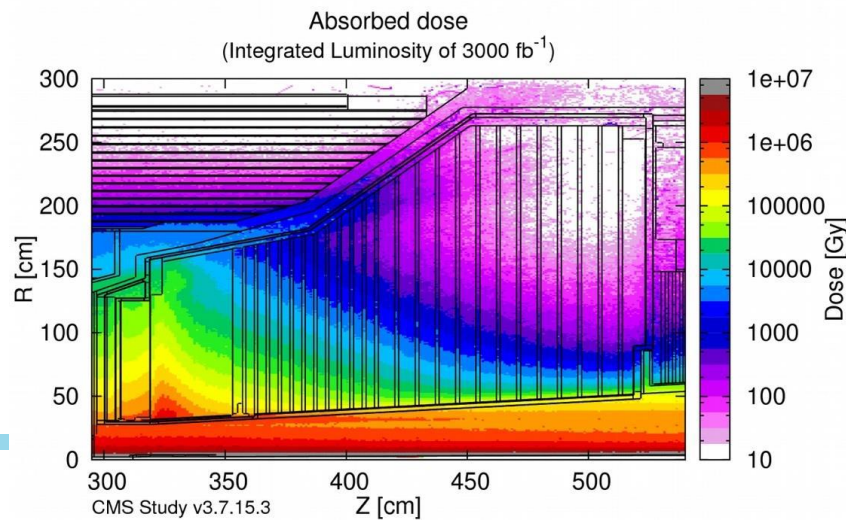
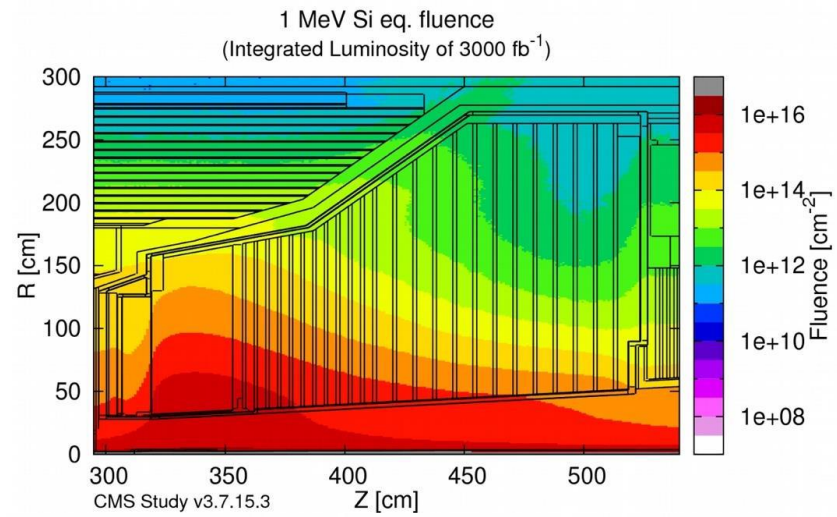
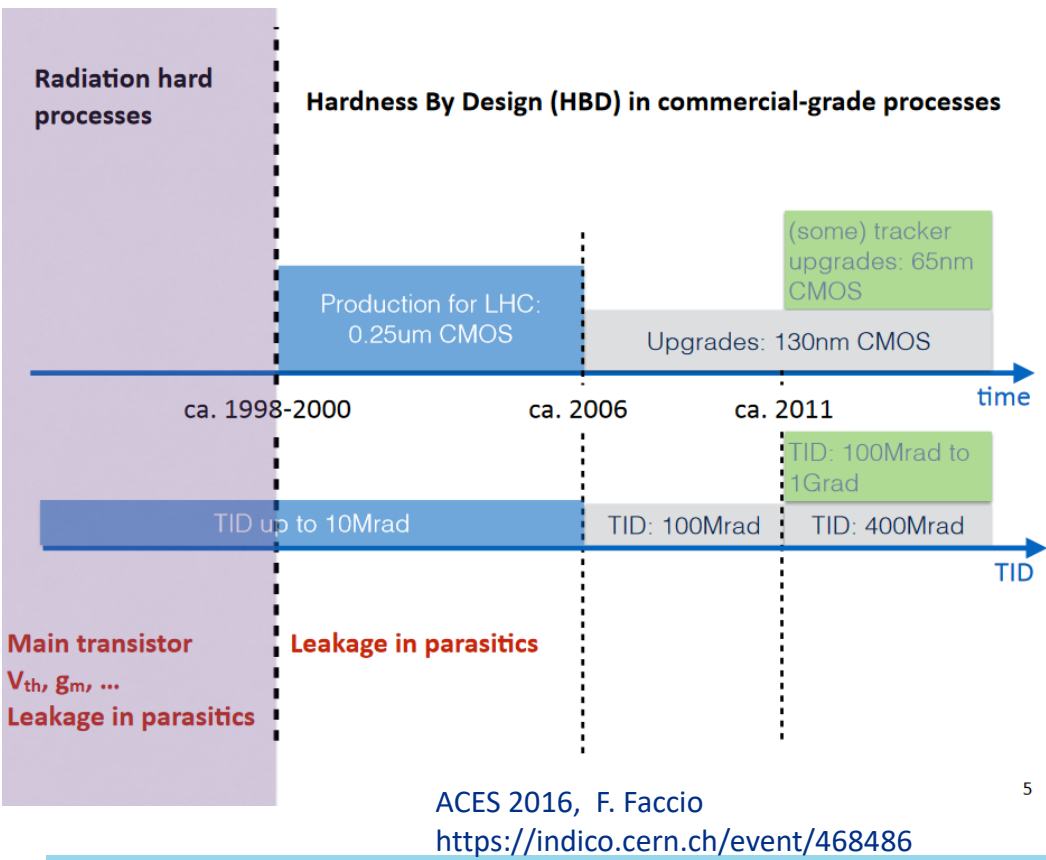


## Complexity

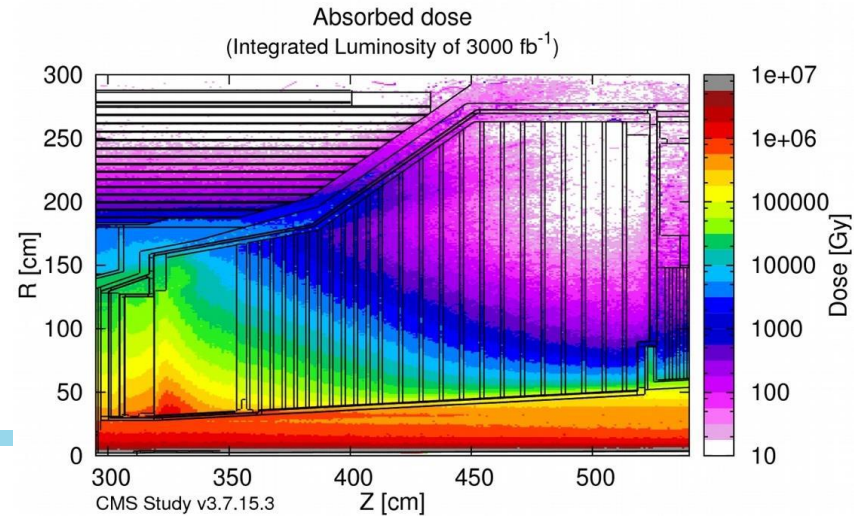
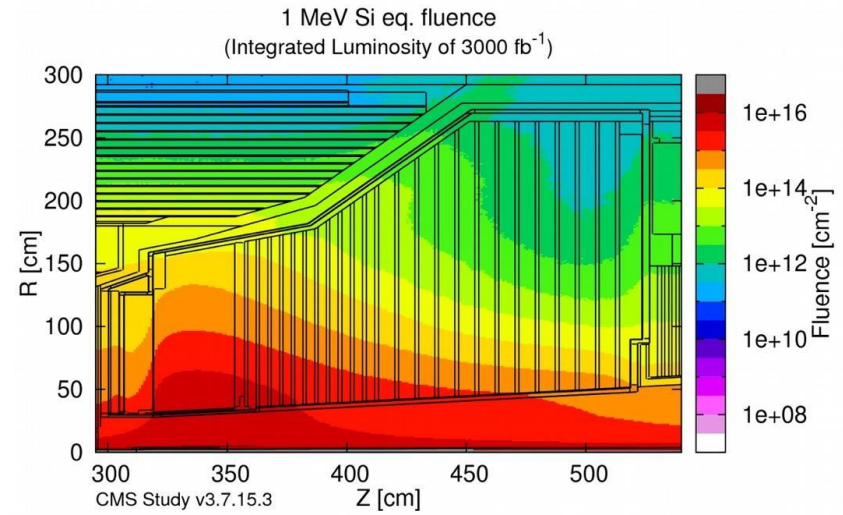
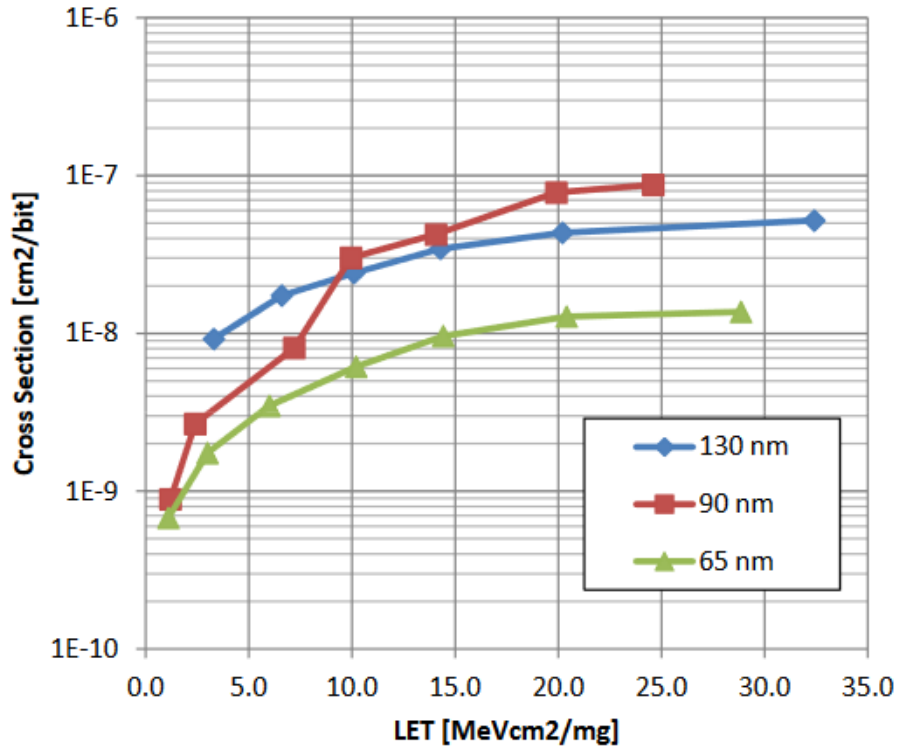




# Need for Extreme Environments



# Need for Extreme Environments



## Performance and Low-Frequency Noise of 22-nm FDSOI Down to 4.2 K for Cryogenic Applications

Bruna Cardoso Paz<sup>✉</sup>, Mikaël Cassé<sup>✉</sup>, *Member, IEEE*, Christoforos Theodorou, Gérard Ghibaudo<sup>✉</sup>, *Fellow, IEEE*, Thorsten Kammler, Luca Pirro, Maud Vinet, *Senior Member, IEEE*, Silvano de Franceschi, Tristan Meunier, and Fred Gaillard

(Invited Paper)

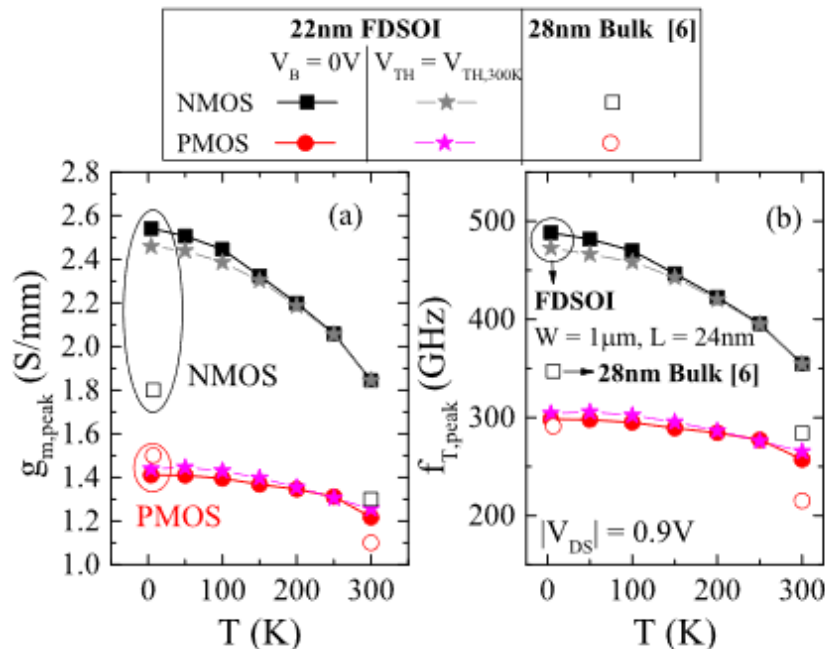


Fig. 5. (a)  $g_{m,peak}$  versus  $T$  and (b)  $f_{T,peak}$  versus  $T$  for nMOS and pMOS, at  $V_B = 0$  V and at  $V_B$  needed to keep  $V_{TH}$  constant =  $V_{TH,300K}$ .  $|V_{DS}| = 0.9$  V.

# Projects within the ASIC group (current, recent and near future)

## CMS Upgrades

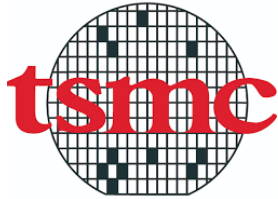
**ECON-T and ECON-D:** data concentrators for trigger and DAQ paths of HGICAL

**ETROC:** precision timing for MIPs in the forward region using LGADs

## DUNE Cold electronics

**COLDADC:** (with LBNL and BNL) 16ch, 12 bit, 2 MSPS ADC

**COLDATA:** “Digital-on-Top” leveraging FNAL cold models.  $<1E-15$  BER @25m and 1.28gbps



**65nm**



**GLOBALFOUNDRIES®**

**22nm FD SOI**



# Projects within the ASIC group (current, recent and near future)

## Quantum projects

**MIDNA**: readout of Skipper CCDs to allow large number of channels

**SNSPD**: readout of Superconducting Nanowire Single Photon Detector (part of QuantISED)

**ACC1**: Atomic Clock Control – shrinking Atomic Clocks to be chip sized (part of QuantISED)

**CITC1**: Cryo-electronics Ion Trap control for Qubits and other quantum applications

**CryoADC**: Collaboration with Microsoft, component for quantum computing

**Skipper in CMOS** (R&D) : extending Skipper technology to CMOS sensors

**SiSeRO** (R&D) : Joint development with MIT LL to extend Skipper technology to MIT-LL process

## Other:

**FALCON**: High speed Xray camera for APS upgrade at ANL

**VIPRAM (130nm)**: 3D CAM (Vertically Integrated Pattern Recognition Associative Memory)

## Take Home Message

One Size does NOT fit all.

Fermilab ASIC group is here to do apply expertise in

**Integrated Circuits** to our **Specific Applications**



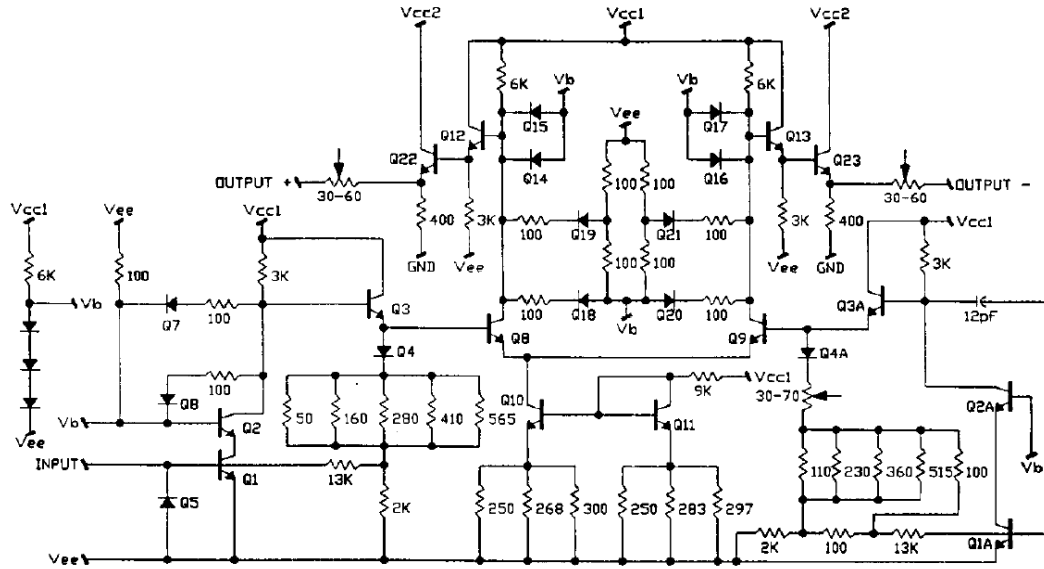
# BACKUP

# Backup: MPW prices from Europractice

## GLOBALFOUNDRIES

Technology	Standard EUR / mm <sup>2</sup>	Discounted EUR / mm <sup>2</sup>
GLOBALFOUNDRIES SiGe 8HP	3,800 <sup>1</sup>	3,600 <sup>1</sup>
GLOBALFOUNDRIES 130 nm BCDlite	1,500 <sup>2</sup>	1,400 <sup>2</sup>
GLOBALFOUNDRIES 130 nm LP	1,500 <sup>2</sup>	1,400 <sup>2</sup>
GLOBALFOUNDRIES 90WG Silicon Photonics	5,250 <sup>1</sup>	5,000 <sup>1</sup>
GLOBALFOUNDRIES 55 nm LPx-NVM/LPx-RF	4,000 <sup>2</sup>	3,800 <sup>2</sup>
GLOBALFOUNDRIES 55 nm LPe	4,000 <sup>2</sup>	3,800 <sup>2</sup>
GLOBALFOUNDRIES 45RFSOI	7,350 <sup>2</sup>	7,000 <sup>2</sup>
GLOBALFOUNDRIES 40 nm LP/LP-RF/RF-mmWave	5,000 <sup>2</sup>	4,700 <sup>2</sup>
GLOBALFOUNDRIES 28 nm SLP/SLP-RF	10,200 <sup>2</sup>	9,700 <sup>2</sup>
GLOBALFOUNDRIES 22 nm FDSOI	14,000 <sup>2</sup>	13,200 <sup>2</sup>

# BACKUP: QPA02



4 chan

Gain = 17mv/fC

ENC = 1600e @ 20pF

Rise = 6 ns

Falltime = 12ns

Power = 42 mw/channel

## QPA02 Schematic Diagram

R. Yarema, "ASIC Design at Fermilab", FERMILAB-Conf-91/170

